

**Search Notes**

Application/Control No.

10/724,415

Examiner

Richard Chan

Applicant(s)/Patent under  
Reexamination

PAI ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
455	181.1	7/6/2006	RC
455	244.1	7/7/2006	RC
455	230	7/7/2006	RC
331	16	7/6/2006	RC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Calibration near 4 cycle and time adj constant	7/7/2006	RC